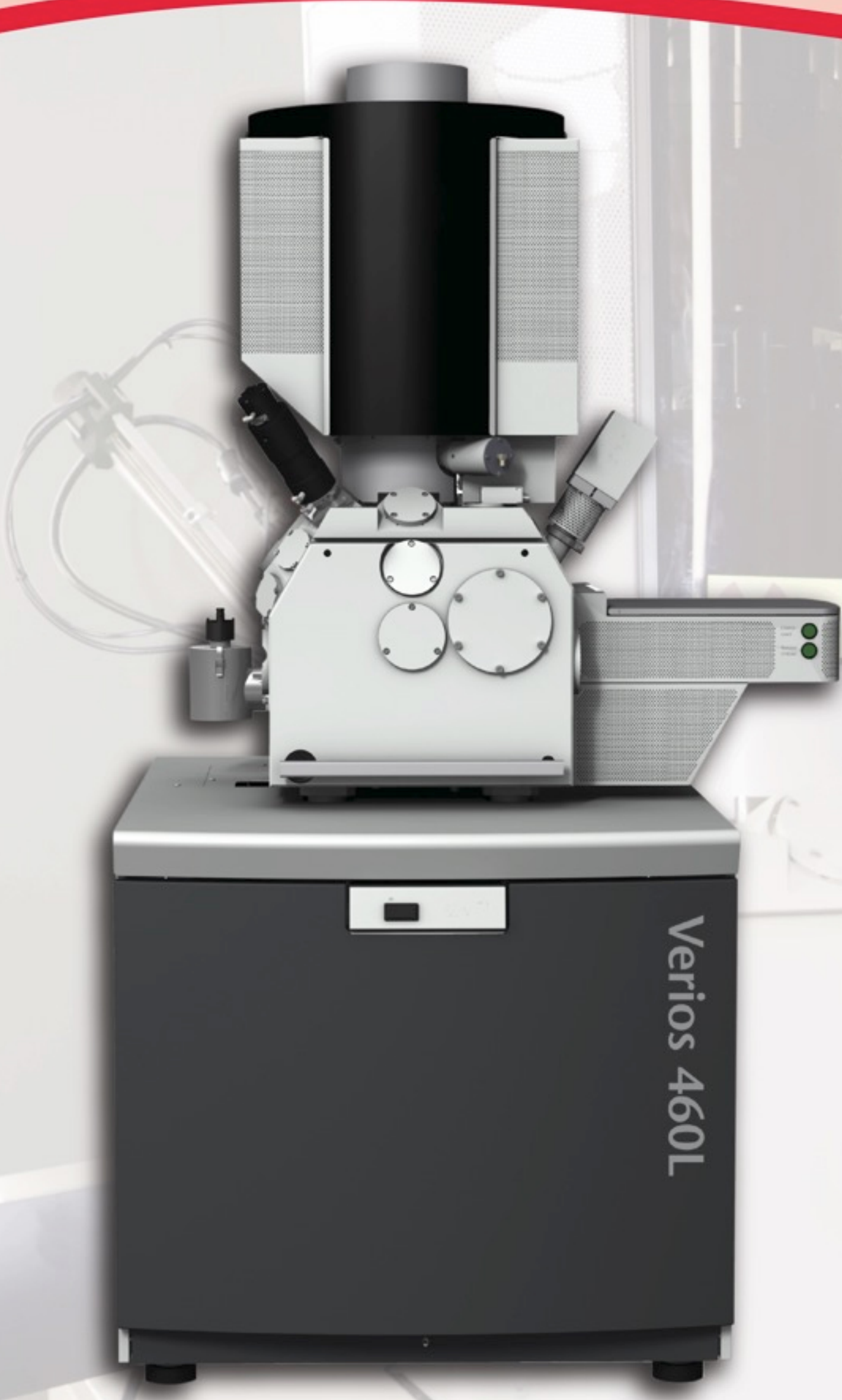


# VERIOS

## Verios 460L SEM



- High resolution imaging to the nanoscale with multiple detectors for topographic and compositional material information
- High flexibility in loading samples gives additional options for analyses



Electron Backscatter Diffraction of additively manufactured steel depicts crystal orientation.



Extreme magnification imaging possible with Verios. Coated nanoparticles at 500,000x magnified.



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